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Table of Contents

Foreword ... ix
Organizing Committee ... x
Program Committee ... xii
Steering Committee ... xiv
Tutorials ... xv
Keynotes ... xvi
Sponsors ... xix
Call for Papers ... xx

2021 IEEE 30th Asian Test Symposium

ChaoPIM: A PIM-based Protection Framework for DNN Accelerators Using Chaotic Encryption . 1
Ning Lin (Institute of Computing Technology, Chinese Academy of Sciences; University of Chinese Academy of Sciences), Xiaoming Chen (Institute of Computing Technology, Chinese Academy of Sciences; University of Chinese Academy of Sciences), Chunwei Xia (Institute of Computing Technology, Chinese Academy of Sciences; University of Chinese Academy of Sciences), Jing Ye (Institute of Computing Technology, Chinese Academy of Sciences; University of Chinese Academy of Sciences), and Xiaowei Li (Institute of Computing Technology, Chinese Academy of Sciences; University of Chinese Academy of Sciences)

Twine Stack: A Hybrid Mechanism Achieving Less Cost for Return Address Protection ... 7
Qizhen Xu (Institute of Information Engineering, Chinese Academy of Sciences; University of Chinese Academy of Sciences), Liwei Chen (Institute of Information Engineering, Chinese Academy of Sciences; University of Chinese Academy of Sciences), and Gang Shi (Institute of Information Engineering, Chinese Academy of Sciences; University of Chinese Academy of Sciences)

Lightweight Hardware-Based Memory Protection Mechanism on IoT Processors ... 13
Hung-Yao Chi (National Cheng Kung University, Taiwan), Kuen-Jong Lee (National Cheng Kung University, Taiwan), and Tzu-Chun Jao (National Cheng Kung University, Taiwan)

Application of Residue Sampling to RF/AMS Device Testing ... 19
Shogo Katayama (Gunma University, Japan), Yudai Abe (Gunma University, Japan), Anna Kuwana (Gunma University, Japan), Koji Asami (Advantest Laboratories Ltd., Japan), Masahiro Ishida (Advantest Corporation, Japan), Ryuya Ohta (Gunma University, Japan), and Haruo Kobayashi (Gunma University, Japan)

Robust Fault-Tolerant Design Based on Checksum and On-Line Testing for Memristor Neural Network ... 25
Michihiro Shintani (Nara Institute of Science and Technology, Japan), Mamoru Ishizaka (Nara Institute of Science and Technology, Japan), and Michiko Inoue (Nara Institute of Science and Technology, Japan)

Temperature-Aware Evaluation and Mitigation of Logic Soft Errors Under Circuit Variations ... 31
Warin Sootkaneung (Rajamangala University of Technology Phra Nakhon, Thailand), Sasithorn Chookaew (King Mongkut's University of Technology North Bangkok, Thailand), and Suppachai Howimanporn (King Mongkut's University of Technology North Bangkok, Thailand)

Note on CapsNet-Based Wafer Map Defect Pattern Classification 37
Itsuki Fujita (Tokyo Metropolitan University, Japan), Yoshikazu Nagamura (Tokyo Metropolitan University, Japan), Masayuki Arai (Nihon University, Japan), and Satoshi Fukumoto (Tokyo Metropolitan University, Japan)

SeGa: A Trojan Detection Method Combined With Gate Semantics 43
Yunying Ye (University of Chinese Academy of Sciences), Shan Li (University of Chinese Academy of Sciences), Haihua Shen (University of Chinese Academy of Sciences), Huawei Li (State Key Laboratory of Computer Architecture Institute of Computing Technology, Chinese Academy of Sciences), and Xiaowei Li (State Key Laboratory of Computer Architecture Institute of Computing Technology, Chinese Academy of Sciences)

CausalTester: Measuring the Consistency of Replicated Services via Causality Semantics 49
Yu Tang (Beihang University, China; Beijing Advanced Innovation Center for Big Data and Brain Computing, China), Le Zhao (Chengdu Aircraft Design & Research Institute, China), Wei Yuan (Beihang University, China; Beijing Advanced Innovation Center for Big Data and Brain Computing, China), and Xu Wang (Beihang University, China; Beijing Advanced Innovation Center for Big Data and Brain Computing, China)

Detection of Stuck-at and Bridging Fault in Reversible Circuits using an Augmented Circuit...... 55
Mousum Handique (Assam University, India), Jantindra Kumar Deka (Indian Institute of Technology Guwahati, India), and Santosh Biswas (Indian Institute of Technology Bhilai, India)

Fault Analysis of the Beam Acceleration Control System at the European XFEL using Data Mining 61
Arne Grünhagen (Hamburg University of Applied Sciences, Germany; German Electron Synchrotron, Germany; Hamburg University of Technology, Germany), Julien Branlard (German Electron Synchrotron, Germany), Annika Eichler (German Electron Synchrotron, Germany), Gianluca Martino (Hamburg University of Technology, Germany; German Electron Synchrotron, Germany), Görschwin Fey (Hamburg University of Technology, Germany), and Marina Tropmann-Frick (Hamburg University of Applied Sciences, Germany)

A Novel Compaction Approach for SBST Test Programs 67
Juan David Guerrero Balaguera (Department of Control and Computer Engineering, Politecnico di Torino, Italy), Josie Esteban Rodriguez Condia (Department of Control and Computer Engineering, Politecnico di Torino, Italy), and Matteo Sonza Reorda (Department of Control and Computer Engineering, Politecnico di Torino, Italy)

Effective SAT-based Solutions for Generating Functional Sequences Maximizing the Sustained Switching Activity in a Pipelined Processor 73
Nikolaos Deligiannis (Politecnico di Torino, DAUIN, Italy), Riccardo Cantoro (Politecnico di Torino, DAUIN, Italy), Tobias Faller (University of Freiburg, Germany), Tobias Paxian (University of Freiburg, Germany), Bernd Becker (University of Freiburg, Germany), and Matteo Sonza Reorda (Politecnico di Torino, DAUIN, Italy)

Side-Channel Attacks on Triple Modular Redundancy Schemes 79
Felipe Almeida (Tallinn University of Technology, Estonia), Levent Aksoy (Tallinn University of Technology, Estonia), Jaan Raik (Tallinn University of Technology, Estonia), and Samuel Pagliarini (Tallinn University of Technology, Estonia)

Polynomial Formal Verification of Prefix Adders 85
Alireza Mahzoon (University of Bremen, Germany) and Rolf Drechsler (University of Bremen, Germany)

Further Analysis of Laser-induced IR-drop 91
William Souza da Cruz (Mines de Saint-Étienne, CEA-LETI, France), Raphael Viera (Mines de Saint-Étienne, CEA-LETI, France), Jean-Max Dutertre (Mines de Saint-Étienne, CEA-LETI, France), Jean-Baptiste Rigaud (Mines de Saint-Étienne, CEA-LETI, France), and Guillaume Hubert (ONERA, France)

Investigation of 0.18μm CMOS Sensitivity to BTI and HCI Mechanisms under Extreme Thermal Stress Conditions 97
Yen Tran (Bordeaux university, France), Toshihiro Nomura (Etudes et Production Schlumberger, France), Mohamed Salim Cherchali (Etudes et Production Schlumberger, France), Claire Tassin (Etudes et Production Schlumberger, France), Yann Deval (Bordeaux University, France), and Cristell Maneux (Bordeaux university, France)

On Modeling CMOS Library Cells for Cell Internal Fault Test Pattern Generation 103
Xijiang Lin (Siemens Digital Industries Software, USA), Wu-Tung Cheng (Siemens Digital Industries Software, USA), Takeo Kobayashi (Siemens Digital Industries Software, USA), and Andreas Glowatz (Siemens Digital Industries Software, USA)

Positive and Negative Extra Clocking of LFSR Seeds for Reduced Numbers of Stored Tests 109
Irith Pomeranz (Purdue University, U.S.A.)

Towards a Secure Integrated Heterogeneous Platform via Cooperative CPU/GPU Encryption . 115
Zhendong Wang (University of Texas at Dallas), Rujia Wang (Illinois Institute of Technology), Zihang Jiang (Tsinghua University), Xulong Tang (University of Pittsburgh), Shouyi Yin (Tsinghua University), and Yang Hu (University of Texas at Dallas)

A Design of Approximate Voting Schemes for Fail-Operational Systems 121
Hideyuki Ichihara (Hiroshima City University, Japan), Kazunori Yukihiro (Hiroshima City University, Japan), and Tomoo Inoue (Hiroshima City University, Japan)

GPU-Accelerated Timing Simulation of Systolic-Array-Based AI Accelerators 127
Stefan Holst (Kyushu Institute of Technology, Japan), Lim Bumun (Kyushu Institute of Technology, Japan), and Xiaoqing Wen (Kyushu Institute of Technology, Japan)

Analyzing Transient Faults and Functional Error Rates of a RISC-V Core: A Case Study 133
Dun-An Yang (National Tsing Hua University, Taiwan), Jing-Jia Liou (National Tsing Hua University, Taiwan), and Harry Chen (MediaTek Inc., Computing and AI Technology Group, Taiwan)

High Precision Measurement of Sub-Nano Ampere Current in ATE Environment 139
Keno Sato (ROHM Semiconductor, Japan), Takayuki Nakatani (Gunma University, Japan), Takashi Ishida (ROHM Semiconductor, Japan), Toshiyuki Okamoto (ROHM Semiconductor, Japan), Tamotsu Ichikawa (ROHM Semiconductor, Japan), Shogo Katayama (Gunma University, Japan), Gaku Ogihara (Gunma University, Japan), Daisuke Iimori (Gunma University, Japan), Yujie Zhao (Gunma University, Japan), Jianglin Wei (Gunma University, Japan), Anna Kuwana (Gunma University, Japan), Kazumi Hatayama (Gunma University, Japan), and Haruo Kobayashi (Gunma University, Japan)

A Power Reduction Method for Scan Testing in Ultra-Low Power Designs 141
Hiroyuki Iwata (Renesas Electronics Corporation, Japan), Yoichi Maeda (Renesas Electronics Corporation, Japan), and Jun Matsushima (Renesas Electronics Corporation, Japan)

Author Index **143**